DOI: 10.1038/srep05690

SUBJECT AREAS:

MECHANICAL
ENGINEERING

ATOMIC FORCE MICROSCOPY

CORRIGENDUM: Characterization of nanoscale temperature fields during electromigration of nanowires

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SCIENTIFIC REPORTS:

4 : 4975

DOI: 10.1038/srep04975
(2014)

The Supplementary Information that accompanies this study was omitted from the original version of this Article.

Published:

15 May 2014

Updated:

16 July 2014